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Search Results -

Term	Documents
(5 AND 15).PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD.	10
(L15 AND L5).PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD.	10

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L17

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side by side			result set
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR</i>			
<u>L17</u>	L15 and 15	10	<u>L17</u>
<u>L16</u>	L15 and 14	28	<u>L16</u>
<u>L15</u>	L12 and token\$1	97	<u>L15</u>
<u>L14</u>	L12 and 15	197	<u>L14</u>
<u>L13</u>	L12 and 14	407	<u>L13</u>
<u>L12</u>	11 and number\$1 near5 (instruction\$1)	800	<u>L12</u>
<u>L11</u>	L9 and 15	10	<u>L11</u>
<u>L10</u>	L9 and 14	32	<u>L10</u>
<u>L9</u>	11 and token\$1	195	<u>L9</u>
<i>DB=PGPB,USPT; PLUR=YES; OP=OR</i>			
<u>L8</u>	11 and token\$1	194	<u>L8</u>

<u>L7</u>	l3 and l5	27	<u>L7</u>
<u>L6</u>	l3 and l4	40	<u>L6</u>
<u>L5</u>	(712/230-241)[CCLS]	1743	<u>L5</u>
<u>L4</u>	(712/2-300)[CCLS]	10928	<u>L4</u>
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR</i>			
<u>L3</u>	L1 near25 (indicat\$4 or token\$1 or detect\$4 or determinat\$4) near8 instruction\$1	74	<u>L3</u>
<u>L2</u>	L1 near25 token\$1 near8 number\$1	0	<u>L2</u>
<u>L1</u>	branch\$3 near5 (true or false)	2549	<u>L1</u>

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Results for "((branch* <near/12> (true,false))<in>metadata)<and>(instruction*<in>metadata))"

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IEEE CNF IEEE Conference Proceeding

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IEEE STD IEEE Standard

1. Design evaluation of pipelined processors using finite state machine analysis with Markov chains

Unwala, I. H.; Cragon, H. G.;
Economics of Design, Test, and Manufacturing, 1994. Proceedings., Third International Conference on the
16-17 May 1994 Page(s):147

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2. A simple mechanism to deal with sequential code in dataflow architectures

Cavenaghi, M.A.; Travieso, G.; Neto, A.G.;
High Performance Computing, 1998. HIPC '98. 5th International Conference On
17-20 Dec. 1998 Page(s):188 - 193

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